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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/630,024	07/31/2000	Kevin L. Farley	TAN-2-1502.01.US	4041
²⁴³⁷⁴ VOLPE AND K	7590 06/11/201 KOENIG, P.C.	EXAMINER		
DEPT. ICC	,	CHAN, RICHARD		
UNITED PLAZA, SUITE 1600 30 SOUTH 17TH STREET PHILADELPHIA, PA 19103			ART UNIT	PAPER NUMBER
			2618	
			MAIL DATE	DELIVERY MODE
			06/11/2010	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of Panel Decision
from Pre-Appeal Brief
Review

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/630,024	FARLEY ET AL.	
	Art Unit	
RICHARD CHAN	2618	

This is in response to the Pre-Appea	I Brief Request for Review filed	
 Improper Request – The I reason(s): 	Request is improper and a conference	e will not be held for the following
☐ The request does not inc	s not been filed concurrent with the Pr clude reasons why a review is appropr is included with the Pre-Appeal Brief	iate.
	nse continues to run from the receipt ommunication, if no Notice of Appeal h	
held. The application remains un is required to submit an appeal b brief will be reset to be one mont running from the receipt of the no	37 CFR 1.136 based upon the mail da	one actual issue for appeal. Applicant . The time period for filing an appeal llance of the two-month time period Further, the time period for filing of the
☐ The panel has determing Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: 44-72. Claim(s) withdrawn from co	-	ows:
	conference has been held. The reject cution on the merits remains closed. N	
	conference has been held. The reject action is required by applicant at this	
All participants:		
(1) <u>RICHARD CHAN</u> .	(3) <u>DUC NGU</u>	<u>YEN</u> .
(2) <u>NAY MAUNG</u> .	(4)	
/RICHARD CHAN/ Examiner, Art Unit 2618	/Nay A. Maung/ Supervisory Patent Examiner, Art Unit 2618	/Duc Nguyen/ Supervisory Patent Examiner, Art Unit 2618